



171023170 Adding Second Assembly & Test Source C8051F85x, C8051F86x, & EFM8BB1 QFN20

PCN Issue Date: 10/23/2017

Effective Date: 1/26/2018

PCN Type: Assembly; Test

Description of Change

Silicon Labs is pleased to announce the successful qualification of Advanced Semiconductor Engineering ChungLi (ASECL) as an additional IC assembly and test site for C8051F85x, C8051F86x, and EFM8BB1 in QFN20 packages. ASECL is an existing IC assembly supplier for Silicon Labs, certified and registered to ISO9001, ISO14001 and TS16949.

After the PCN effective date, Silicon Labs will ship product from either qualified assembly site.

Reason for Change

Capacity expansion

Impact on Form, Fit, Function, Quality, Reliability

There is no impact on fit, function, quality, or reliability. The form has changed to include Cu wire bonds.

Product Identification

EFM8BB10F4G-A-QFN20
EFM8BB10F4G-A-QFN20R
EFM8BB10F4I-A-QFN20
EFM8BB10F4I-A-QFN20R
EFM8BB10F8G-A-QFN20
EFM8BB10F8G-A-QFN20R
EFM8BB10F8I-A-QFN20
EFM8BB10F8I-A-QFN20R
EFM8BB10F2G-A-QFN20
EFM8BB10F2G-A-QFN20R
EFM8BB10F2I-A-QFN20
EFM8BB10F2I-A-QFN20R
EFM8BB10M1039F8GM-A
EFM8BB10M1039F8GM-AR
EFM8BB10M1069F8GM-A
EFM8BB10M1069F8GM-AR
EFM8BB10P1012F2GM-A
EFM8BB10P1012F2GM-AR
EFM8BB10P1072F4GM-A
EFM8BB10P1072F4GM-AR
C8051F850-C-GM
C8051F850-C-GMR
C8051F850-C-IM
C8051F850-C-IMR
C8051F851-C-GM
C8051F851-C-GMR
C8051F851-C-IM
C8051F851-C-IMR
C8051F852-C-GM

C8051F852-C-GMR
C8051F852-C-IM
C8051F852-C-IMR
C8051F853-C-GM
C8051F853-C-GMR
C8051F853-C-IM
C8051F853-C-IMR
C8051F854-C-GM
C8051F854-C-GMR
C8051F854-C-IM
C8051F854-C-IMR
C8051F855-C-GM
C8051F855-C-GMR
C8051F855-C-IM
C8051F855-C-IMR
CF850P1102CGM
CF850P1102CGMR

Last Date of Unchanged Product: 1/26/2018

Qualification Samples

Available on request.

Specific conditions of acceptance of this change will be considered on a case by case basis if written notice is submitted within 30 days of this notice. To request further data or inquire about this notification, please contact your local Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at <http://www.silabs.com>.

In some cases rejection of a change notice may impact Silicon Labs product pricing, delivery, quality, or reliability.

Customer Early Acceptance Sign Off

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance:

Date: _____

Name: _____

Company: _____

Email your early Acceptance approval to: PCNEarlyAcceptance@silabs.com

User Registration

Register today to create your account on Silabs.com. Your personalized profile allows you to receive technical document updates, new product announcements, "how-to" and design documents, product change notices (PCN) and other valuable content available only to registered users. <http://www.silabs.com/profile>

Qualification Data

See attached qualification reports below.

C8051F85x.86x AEC-Q100 Qualification Report



W7101F1 - Product Qualification Plan and Report Record Rev. G

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C8051F85x.86x Rev C, GSMC Fabrication, UTACTH and ASECL Assembly except as noted							
Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A - Accelerated Environment Stress Tests - 24-QSOP - UTACTH CuPd Wire							
THB	JA101 85°C, 85%RH Vcc=3.6V, 1000 hours	3 lots, N=>77	Q34377	0/79	1		Pass
			Q34374	0/80	1	3 lots	
			Q34090	0/80	1	0/239	
UHASt	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q34376	0/80	1		Pass
			Q34373	0/80	1	3 lots	
			Q34089	0/80	1	0/240	
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>77	Q34375	0/80	1		Pass
			Q34372	0/80	1	3 lots	
			Q34088	0/80	1	0/240	
HTSL	JA103 150°C, 1000hr	1 lot, N=>45	Q34120	0/81	1		Pass
			Q34432	0/85	1	2 lots 0/166	
Test Group A - Accelerated Environment Stress Tests - 20-QFN-3x3 - UTACTH Au Wire							
HASt	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q34390	0/80	1		Pass
			Q34384	0/80	1	3 lots	
			Q34193	0/80	1	0/240	
UHASt	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q34386	0/80	1		Pass
			Q34383	0/80	1	3 lots	
			Q34184	0/80	1	0/240	
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>77	Q34385	0/80	1		Pass
			Q34382	0/80	1	4 lots	
			Q34192	0/80	1	0/317	
			Q40860	0/77	1		
HTSL	JA103 150°C, 1000hr	1 lot, N=>45	Q34342	0/50	1	1 lots 0/50	Pass

Approved by: Vincent Hidajat

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Prepared on: 23-Feb-17

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Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group A - Accelerated Environment Stress Tests - 20-QFN-3x3 - ASECL CuPd Wire							
HAST	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q035864	0/80	1		Pass
			Q035863	0/80	1	3 lots	
			Q035862	0/80	1	0/240	
UHAST	JA110 130°C, 85%RH Vcc=3.6V, 192 hours	3 lots, N=>77	Q035861	0/84	1		Pass
			Q035859	0/85	1	3 lots	
			Q035858	0/81	1	0/250	
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>77	Q035857	0/85	1		Pass
			Q035856	0/78	1	3 lots	
			Q035855	0/85	1	0/248	
HTSL	JA103 150°C, 1000hr	1 lot, N=>45	Q035854	0/30	1		Pass
			Q035847	0/30	1	3 lots	
			Q035846	0/30	1	0/90	
Test Group A - Accelerated Environment Stress Tests - 16-SOIC - UTACTH Au Wire							
HAST	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q34364	0/78	1		Pass
			Q34361	0/80	1	3 lots	
			Q34191	0/80	1	0/238	
UHAST	JA110 130°C, 85%RH Vcc=3.6V, 96 hours	3 lots, N=>77	Q34363	0/80	1		Pass
			Q34359	0/80	1	3 lots	
			Q34189	0/78	1	0/238	
Temp Cycle	JA104 Cond C: -65°C to 150°C 500 cycles	3 lots, N=>77	Q34362	0/80	1		Pass
			Q34360	0/80	1	3 lots	
			Q34190	0/80	1	0/240	
HTSL	JA103 150°C, 1000hr	1 lot, N=>45	Q34334	0/50	1	1 lots 0/50	Pass

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Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status
Test Group B - Accelerated Lifetime Simulation Tests							
HTOL	JA108 125°C, Dynamic Vcc=3.6V, 1000 hours	3 lots, N=>77	Q34435	0/15	6		Pass
			Q34434	0/84	6		
			Q34753	0/99	6	4 lots	
			Q34773	0/88	6	0/286	
ELFR	AEC-Q100-008 125°C, Dynamic Vcc=3.6V, 48 hours	3 lots, N=>800	Q34414	0/809		3 lots	Pass
			Q34752	0/826			
			Q34012	0/829		0/2464	
HTDR	AEC-Q100-005 150°C, 1000 hours	3 lots, N=>77	Q34432	0/85	6		Pass
			Q34433	0/15	6		
			Q34775	0/99	6	7 lots	
			Q34774	0/100	6	0/579	
			Q35080	0/86	8		
			Q35081	0/87	8		
LTDR	AEC-Q100-005 25°C, 1000 hours	3 lots, N=>77	Q34436	0/82	7		Pass
			Q34778	0/100	7		
			Q34776	0/100	7	4 lots	
			Q34437	0/15	7	0/297	
Test Group E - Electrical Verification							
ESD-HBM	AEC-Q100-002	1 lot, N=>3	Q34017				2000 V
ESD-MM	AEC-Q100-003	1 lot, N=>3	Q34018				150 V
ESD-CDM	AEC-Q100-011	1 lot, N=>3	Q34457		2		1250 V
			Q34415		3		1250 V
			Q34481		4		1500 V
			Q35881		5		1500 V
Latch Up	AEC-Q100-004 ±200mA	1 lot, N=>6	Q34412 Q24413	125 C 25 C			Pass
Gate Leakage	AEC-Q100-006	1 lot, N=>6	Q34211				Pass

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Test Name	Test Condition	Qualification	Lot ID or Start	Fail/Pass or End	Notes	Summary	Status

Notes:

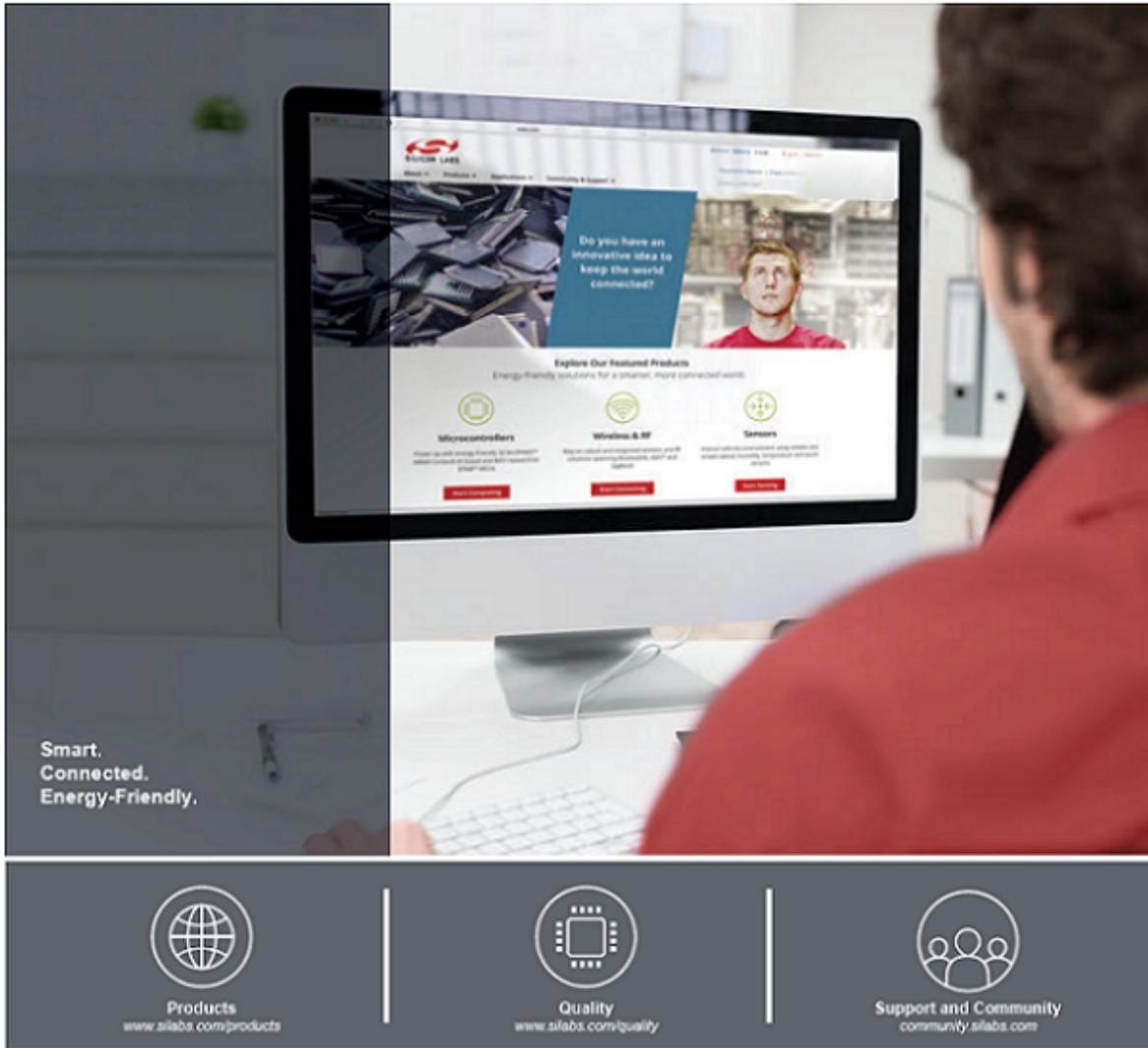
1. Parts are Pre-conditioned at MSL2/260°C
2. 16-SOIC
3. 24-QSOP
4. 20-QFN UTACTH
5. 20-QFN ASECL
6. Device are preconditioned with 20K program/erase endurance cycling at 85°C
7. Device are preconditioned with 20K program/erase endurance cycling at 55°C
8. Device are preconditioned with 20K program/erase endurance cycling at 125°C

This report applies to the following part numbers:				
C8051F850-C-GM	C8051F850-C-GU	C8051F850-C-IM	C8051F850-C-IU	C8051F850-C-YM
C8051F851-C-GM	C8051F851-C-GU	C8051F851-C-IM	C8051F851-C-IU	C8051F850-G1DI
C8051F852-C-GM	C8051F852-C-GU	C8051F852-C-IM	C8051F852-C-IU	C8051F850-GDI
C8051F853-C-GM	C8051F853-C-GU	C8051F853-C-IM	C8051F853-C-IU	
C8051F854-C-GM	C8051F854-C-GU	C8051F854-C-IM	C8051F854-C-IU	
C8051F855-C-GM	C8051F855-C-GU	C8051F855-C-IM	C8051F855-C-IU	
C8051F860-C-GS	C8051F860-C-IS			
C8051F861-C-GS	C8051F861-C-IS			
C8051F862-C-GS	C8051F862-C-IS			
C8051F863-C-GS	C8051F863-C-IS			
C8051F864-C-GS	C8051F864-C-IS			
C8051F865-C-GS	C8051F865-C-IS			

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